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Edition 1.0 2015-08

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Ferrite cores – Guidelines on the limits of surface irregularities – Part 8: PQ-cores

Noyaux ferrites – Lignes directrices relatives aux limites des irrégularités de surface – Partie 8: Noyaux PQ

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

FERRITE CORES – GUIDELINES ON THE LIMITS OF SURFACE IRREGULARITIES –

Part 8: PQ-cores

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International Standard IEC 60424-8 has been prepared by technical committee 51: Magnetic components and ferrite materials.

The text of this standard is based on the following documents:

CDV	Report on voting
51/1078/CDV	51/1084/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60424 series, published under the general title *Ferrite cores – Guidelines on the limits of surface irregularities*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

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FERRITE CORES – GUIDELINES ON THE LIMITS OF SURFACE IRREGULARITIES –

Part 8: PQ-cores

1 Scope

This part of IEC 60424 gives guidance on allowable limits of surface irregularities applicable to PQ-cores in accordance with the relevant generic specification.

This standard is considered as a sectional specification useful in the negotiation between ferrite core manufacturers and users about surface irregularities.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60401-1, *Terms and nomenclature for cores made of magnetically soft ferrites – Part 1: Terms used for physical irregularities*

IEC 60424-1, *Ferrite cores – Guide on the limits of surface irregularities – Part 1: General specification*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60424-1 and IEC 60401-1, as well as the following apply.

3.1
pores
holes left on the surface of cores after sintering and surface finishing

SEE: Figure 1.

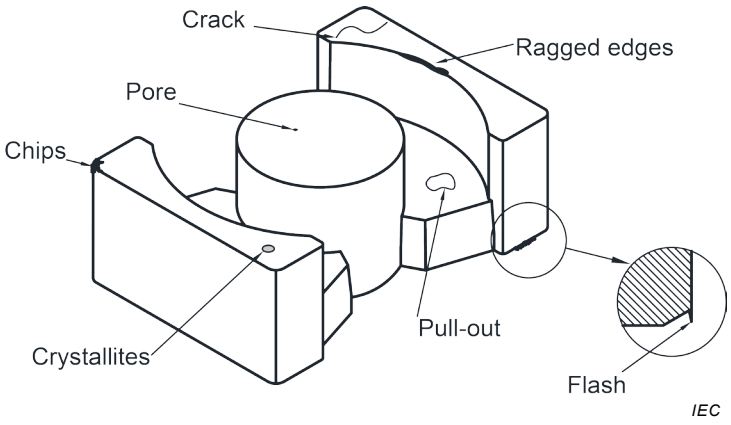


Figure 1 – Examples of surface irregularities

4 Limits of surface irregularities

4.1 Chips and ragged edges

4.1.1 Chips and ragged edges located on the mating surface

The areas of the chips located on the mating surface (see C1 and C1' irregularities in Figure 2) shall not exceed the following limits:

– the cumulative area of the chips located on the mating surface shall be less than 4 % of the total mating surface;

– the cumulative area of the chips located on the centre post mating surface shall be less than 2 % of the total mating surface;

– the cumulative area of the chips located on the mating surface of one outer leg shall be less than 1 % of the total mating surface;

The total length of the ragged edges shall be less than 25 % of the perimeter of the relevant mating surface.

4.1.2 Chips located on other surfaces

The areas of the chips located on the other surfaces (see C2, C2', C3 and C3' irregularities in Figure 2) shall not exceed the following limits:

– the allowable chipping areas are doubled as compared to the limits for the whole mating surfaces (see Table 1);

– the rule for the ragged edges is the same as for the mating surfaces;

– chips and ragged edges are not acceptable on the inner edges of the wire slot area.

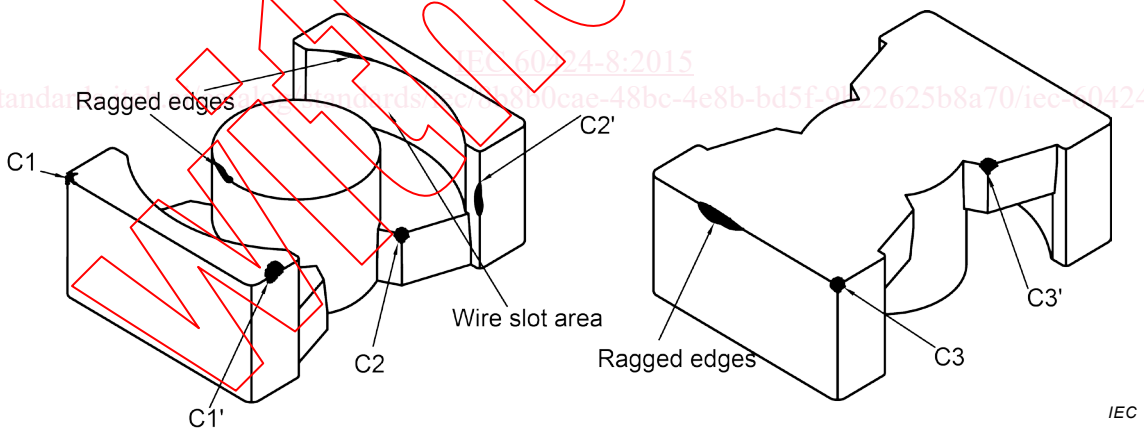


Figure 2 – Chips and ragged edges location

The limits of allowable chipping areas shall be in accordance with Table 1.

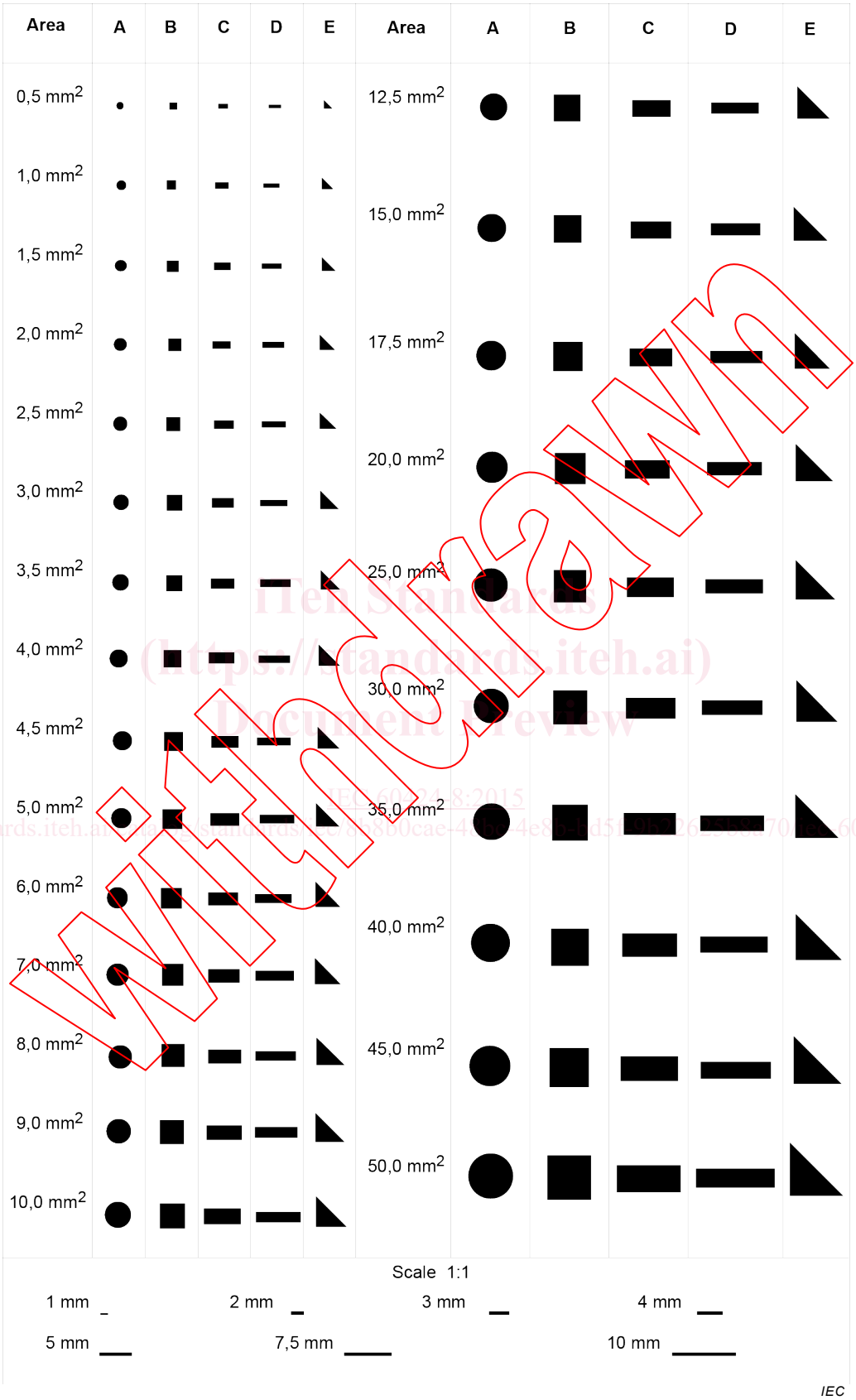
Table 1 – Limits for allowable chipping areas

Unit: mm²

Core size	Chipping on mating surface of one outer leg	Chipping on mating surface of centre post	Overall chipping on mating surface	Overall chipping on other surfaces
PQ20/16	< 1,0	< 2,0	< 4,5	< 9,0
PQ20/20	< 1,0	< 2,0	< 4,5	< 9,0
PQ26/20	< 2,0	< 4,5	< 9,5	< 19,0
PQ26/25	< 2,0	< 4,5	< 9,5	< 19,0
PQ32/20	< 3,0	< 6,0	< 12,0	< 24,0
PQ32/30	< 3,0	< 6,0	< 12,0	< 24,0
PQ35/35	< 3,0	< 6,5	< 13,0	< 26,0
PQ40/40	< 3,5	< 7,0	< 14,0	< 28,0
PQ50/50	< 6,0	< 12,5	< 25,0	< 50,0
NOTE For the relevant core sizes refer to IEC 62317-13.				

The area and length reference of irregularities for visual inspection are given in Table 2.

Table 2 – Area and length reference of irregularities for visual inspection

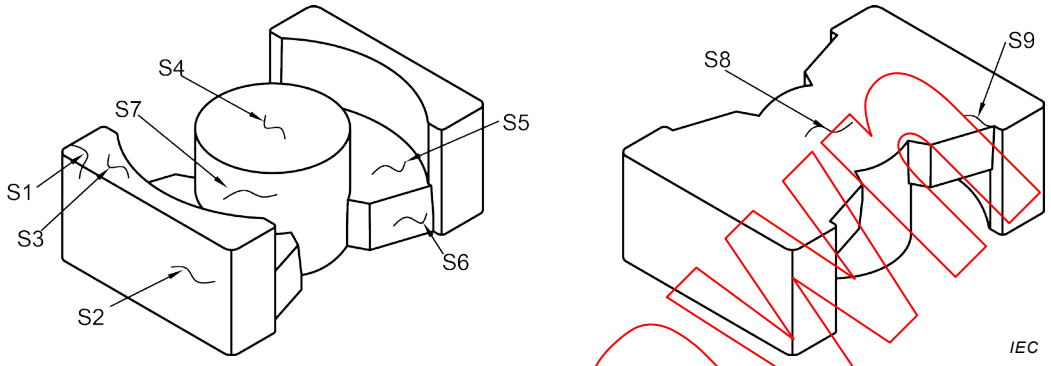


4.2 Cracks

Figure 3 shows examples of cracks location on PQ-cores:

– a single crack which intersects the perimeter of the relevant surface at two points is not acceptable (see S1 in Figure 3);
– the number of the cracks located on the same surface shall not exceed 3.

The limits of cracks at various locations shown in Figure 3 are given in Table 3.

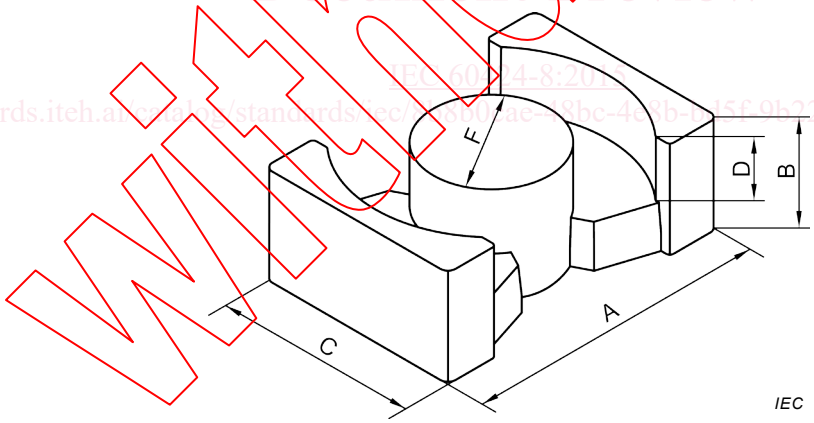


Key

S1 to S8: types of cracks (for limits for cracks, see Table 3)

Figure 3 – Cracks location

The reference dimensions for PQ-cores given in Figure 4 correspond to the cores defined in IEC 60401-2.



Key

A Overall length of the core back
B Outside leg length of core
C Core width
D Inside leg length or available bobbin depth
F Centre post diameter

Figure 4 – Reference dimensions for PQ-cores